TOSHIBA Photocoupler GaAs IRed & Photo-Transistor

# **TLP570,TLP571**

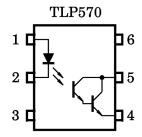
Programmable Controllers
AC / DC-Input Module
Solid State Relay

The TOSHIBA TLP570 and TLP571 consist of a darlington connected photo–transistor optically coupled to a gallium arsenide infrared emitting diode in a six lead plastic DIP package.

TLP570 is no-base internal connection for high-EMI environments.

- Collector-emitter voltage: 35V (min.)
- Current transfer ratio: 1000% (min.)
- Isolation voltage: 2500Vrms (min.)
- UL recognized: UL1577, file no. E67349

#### Pin Configurations (top view)

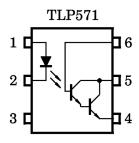


1 : ANODE 2 : CATHODE

3: NC

4 : EMITTER 5 : COLLECTOR

6: NC



1 : ANODE 2 : CATHODE

3: NC

4 : EMITTER 5 : COLLECTOR

6: BASE

Unit in mm

11-7A8

**TOSHIBA** 



#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
	Forward current	lF	70	mA	
	Forward current derating (Ta ≥ 25°C)	ΔI <sub>F</sub> / °C	-0.7	mA / °C	
E	Peak forward current (100µs pulse, 100pps)	I <sub>FP</sub>	1	Α	
	Reverse voltage	V <sub>R</sub>	5	V	
	Junction temperature	Tj	125	°C	
	Collector-emitter voltage	V <sub>CEO</sub>	35	V	
	Collector-base voltage (TLP571)	V <sub>CBO</sub>	80	V	
	Emitter-collector voltage	V <sub>ECO</sub>	7	V	
Detector	Emitter-base voltage (TLP571)	V <sub>EBO</sub>	7	V	
Dete	Collector current	Ic	150	mA	
	Power dissipation	PC	150	mW	
	Power dissipation derating (Ta ≥ 25°C)	ΔP <sub>C</sub> / °C	-1.5	mW / °C	
	Junction temperature	Tj	125	°C	
Stor	age temperature range	T <sub>stg</sub>	<b>−55~125</b>	°C	
Operating temperature range		T <sub>opr</sub>	<b>−55~100</b>	°C	
Lea	d soldering temperature (10s)	T <sub>sold</sub>	260	°C	
Tota	al package power dissipation	P <sub>T</sub>	250	mW	
Tota	al package power dissipation derating (Ta ≥ 25°C)	ΔP <sub>T</sub> / °C	-2.5	mW / °C	
Isola	ation voltage (AC, 1 min., R.H.≤ 60%) (Note 1)	BVS	2500	V <sub>rms</sub>	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Device considered a two terminal: Pins1, 2 and 3 shorted together and pins 4, 5 and 6 shorted together.

#### **Recommends Operating Conditions**

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V <sub>CC</sub>	_	5	24	V
Forward current	lF	_	16	25	mA
Collector current	IC	_	_	50	mA
Operating temperature	T <sub>opr</sub>	-25	_	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.



### Individual Electrical Characteristics (Ta = 25°C)

	Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10 mA	1.0	1.15	1.3	V
LED	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 5 V	_	_	10	μΑ
	Capacitance	C <sub>T</sub>	V = 0, f = 1 MHz	_	30	_	pF
	Collector–emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 1 mA	35	_	_	V
	Emitter-collector breakdown voltage	V <sub>(BR)ECO</sub>	I <sub>E</sub> = 0.1 mA	7	_	_	V
Detector	Collector–base breakdown voltage (TLP571)	V <sub>(BR)CBO</sub>	I <sub>C</sub> = 0.1 mA	80	_	_	V
	Emitter-base breakdown voltage (TLP571)	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 0.1 mA	7	_	_	V
	Collector dark current	I <sub>CEO</sub>	V <sub>CE</sub> = 24 V	_	10	200	nA
			V <sub>CE</sub> = 24 V, Ta = 85°C	_	_	300	μΑ
	Collector dark current (TLP571)	I <sub>CER</sub>	V <sub>CE</sub> = 24 V, Ta = 85°C R <sub>BE</sub> = 10 MΩ	_	0.5	10	μΑ
	Collector dark current (TLP571)	I <sub>CBO</sub>	V <sub>CB</sub> = 10 V	_	0.01	_	nA
	DC forward current gain (TLP571)	h <sub>FE</sub>	V <sub>CE</sub> = 5 V, I <sub>C</sub> = 10 mA		50k		_
	Capacitance (collector to emitter)	C <sub>CE</sub>	V = 0, f = 1 MHz	_	10	_	pF

### **Coupled Electrical Characteristics (Ta = 25°C)**

Characteristic	Symbol	Test Condition	MIn.	Тур.	Max.	Unit
Current transfer ratio	I <sub>C</sub> / I <sub>F</sub>	I <sub>F</sub> = 1 mA, V <sub>CE</sub> = 1 V	1000	2000	_	%
Saturated CTR	I <sub>C</sub> / I <sub>F (sat)</sub>	I <sub>F</sub> = 10 mA, V <sub>CE</sub> = 1 V	500	_	_	%
Base photo-current (TLP571)	I <sub>PB</sub>	I <sub>F</sub> = 1 mA, V <sub>CB</sub> = 1 V	_	2	-	μΑ
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> = 10 mA, I <sub>F</sub> = 1 mA	_	_	1.0	V
		I <sub>C</sub> = 100 mA, I <sub>F</sub> = 10 mA	0.3	_	1.2	



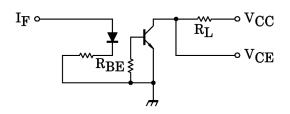
## Isolation Characteristics (Ta = 25°C)

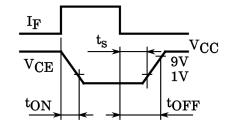
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Capacitance (input to output)	CS	V <sub>S</sub> = 0, f = 1 MHz	_	0.8	_	pF
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500 V, R.H. ≤ 60%	5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
	BVS	AC, 1 minute	2500	_	_	\
Isolation voltage		AC, 1 second, in oil	_	5000	_	V <sub>rms</sub>
		DC, 1 minute, in oil	_	5000	_	V <sub>dc</sub>

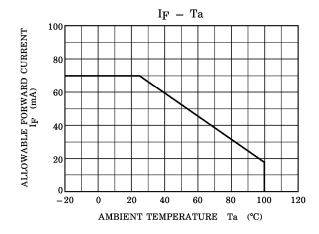
### **Switching Characteristics (Ta = 25°C)**

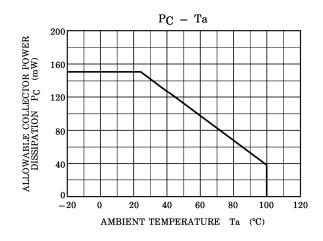
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Rise time	t <sub>r</sub>		_	40	_	
Fall time	t <sub>f</sub>	V <sub>CC</sub> = 10 V	_	30	_	
Turn-on time	t <sub>ON</sub>	$I_C = 10 \text{ mA}$ $R_L = 100\Omega$	_	45	_	μs
Turn-off time	t <sub>OFF</sub>		_	35	_	
Turn-on time	t <sub>ON</sub>	$R_L = 180\Omega$ (Fig.1)	_	5	_	
Storage time	t <sub>s</sub>	R <sub>BE</sub> = open	_	20	_	μs
Turn-off time	t <sub>OFF</sub>	V <sub>CC</sub> = 10 V, I <sub>F</sub> = 10 mA	_	100	_	
Turn-on time	t <sub>ON</sub>	$R_L = 180\Omega$ (Fig.1)	_	5	_	
Storage time	ts	$R_{BE} = 10M\Omega (TLP571)$	_	15	_	μs
Turn-off time	t <sub>OFF</sub>	V <sub>CC</sub> = 10 V, I <sub>F</sub> = 10 mA	_	60	_	

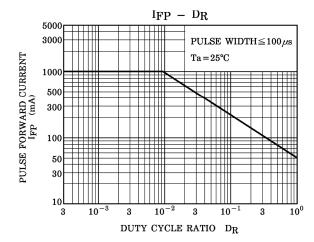
Fig. 1 Switching time test circuit

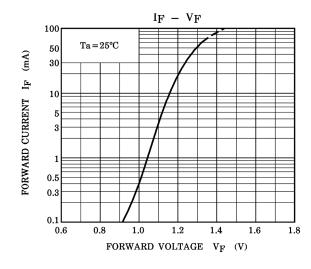


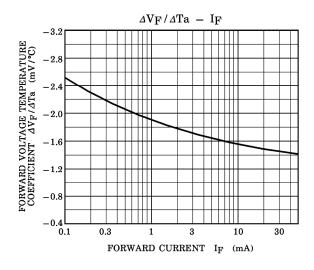


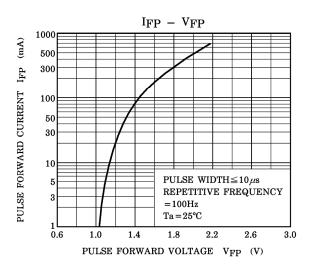


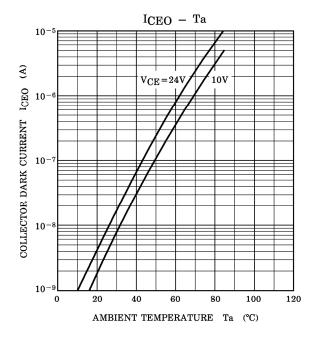


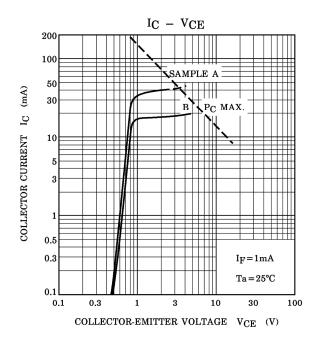


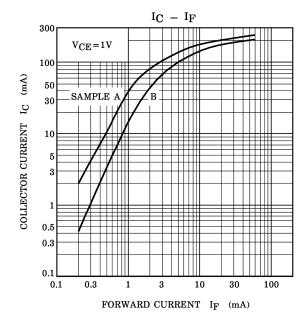


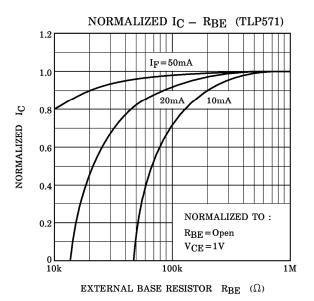






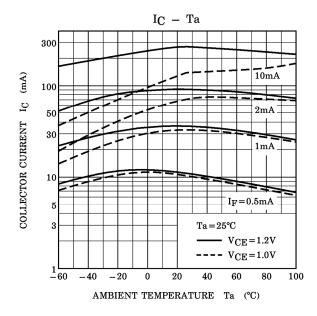


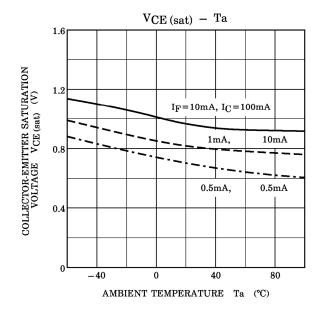


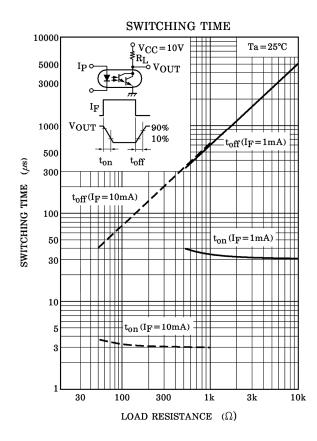


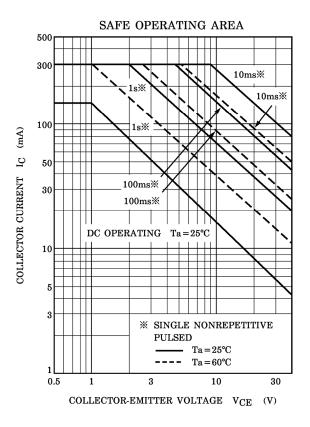
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